







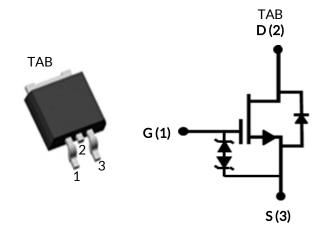








UJ3C065030B3



Part Number	Package	Marking
UJ3C065030B3	D ² PAK-3L	UJ3C065030B3







$650V-27m\Omega$ SiC FET

Rev. C, May 2023

Description

This SiC FET device is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the D 2 PAK-3L package, this device exhibits ultralow gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- \bullet Typical on-resistance $R_{DS(on),typ}$ of $27m\Omega$
- Maximum operating temperature of 175°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- ESD protected: HBM class 2 and CDM class C3

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating















Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		650	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current ¹		T _C = 25°C	65	Α
	I _D	T _C = 100°C	47	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	230	Α
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =4A	120	mJ
Power dissipation	P_{tot}	T _C = 25°C	242	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J, T_{STG}		-55 to 175	°C
Reflow soldering temperature	T_{solder}	reflow MSL 1	245	°C

- 1. Limited by $T_{J,\text{max}}$
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{ heta$ JC			0.48	0.62	°C/W



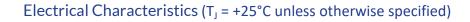












Typical Performance - Static

Parameter	Symbol	Test Conditions		Units		
Parameter			Min	Тур	Max	Units
Drain-source breakdown voltage	BV_DS	$V_{GS}=0V, I_D=1mA$	650			V
Total drain leakage current		V _{DS} =650V, V _{GS} =0V, T _J =25°C		6	150	μΑ
	I _{DSS}	V _{DS} =650V, V _{GS} =0V, T _J =175°C		30		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		6	± 20	μА
Drain-source on-resistance	R _{DS(on)}	V_{GS} =12V, I_{D} =50A, T_{J} =25°C		27	35	
		V _{GS} =12V, I _D =50A, T _J =125°C		35		mΩ
		V_{GS} =12V, I_{D} =50A, T_{J} =175°C		43		
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_{D} =10mA	4	5	6	V
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Linita		
			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C =25°C			65	Α
Diode pulse current ²	I _{S,pulse}	T _C =25°C			230	Α
Forward voltage	V _{FSD}	V _{GS} =0V, I _S =20A, T _J =25°C		1.3	1.4	V
		V _{GS} =0V, I _S =20A, T _J =175°C		1.35		
Reverse recovery charge	Q _{rr}	V_R =400V, I_S =50A, V_{GS} =0V, R_{G_EXT} =20 Ω		400		nC
Reverse recovery time	t _{rr}	di/dt=1550A/μs, Τ _J =150°C		33		ns













Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Units
Input capacitance	C_{iss}	- V _{DS} =100V, V _{GS} =0V - f=100kHz -		1500		
Output capacitance	C_{oss}			320		pF
Reverse transfer capacitance	C_{rss}			2.3		
Effective output capacitance, energy related	$C_{oss(er)}$	V_{DS} =0V to 400V, V_{GS} =0V		230		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS} =0V to 400V, V_{GS} =0V		520		pF
C _{OSS} stored energy	E_{oss}	V_{DS} =400V, V_{GS} =0V		18.5		μJ
Total gate charge	Q_{G}	- V _{DS} =400V, I _D =40A, - V _{GS} = -5V to15V		51		
Gate-drain charge	Q_{GD}			11		nC
Gate-source charge	Q_{GS}			19		
Turn-on delay time	$t_{d(on)}$	V _{DS} =400V, I _D =40A, Gate		32		
Rise time	t_r			19		nc
Turn-off delay time	$t_{d(off)}$	Driver =-5V to +15V,		58		ns
Fall time	t_f	Turn-on $R_{G,EXT}$ =1 Ω , Turn-off $R_{G,EXT}$ =20 Ω Inductive Load, FWD: UJ3D065030TS, T_J =150°C		15		
Turn-on energy	E _{ON}			341		
Turn-off energy	E _{OFF}			180		μЈ
Total switching energy	E _{TOTAL}			521		







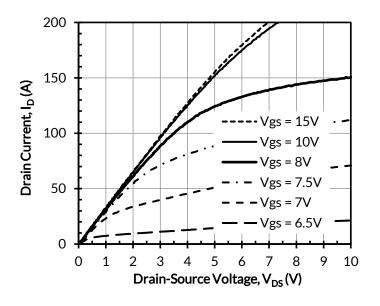








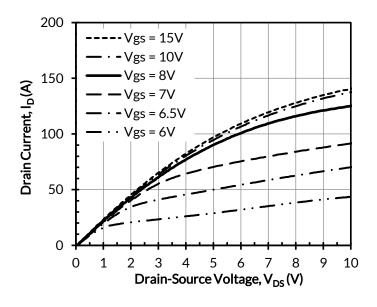
Typical Performance Diagrams



200 150 Drain Current, I_D (A) Vgs = 15V 100 Vgs = 10V Vgs = 8V 50 - Vgs = 7V Vgs = 6.5V 0 1 2 3 5 10 Drain-Source Voltage, $V_{DS}(V)$

Figure 1. Typical output characteristics at T_J = - 55°C, tp < 250 μ s

Figure 2. Typical output characteristics at $T_J = 25$ °C, tp < 250 μ s



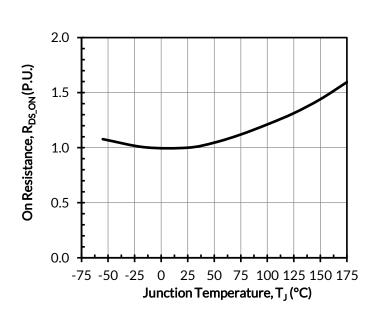


Figure 3. Typical output characteristics at T_J = 175°C, tp < 250 μ s

Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_{D} = 50A



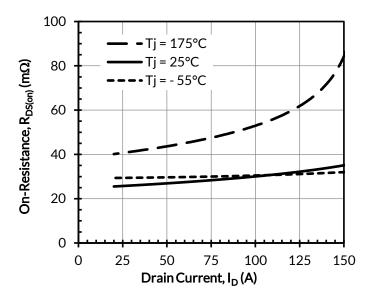








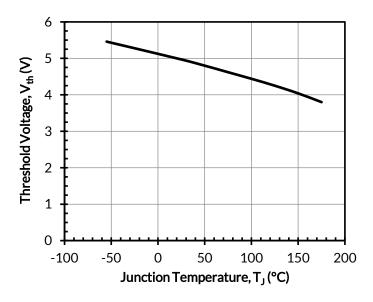




Tj = -55°C Tj = 25°C Drain Current, I_D (A) Tj = 175°C Gate-Source Voltage, $V_{GS}(V)$

Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at V_{DS} = 5V



Gate Charge, Q_G (nC)

Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_{D} = 10mA

Figure 8. Typical gate charge at V_{DS} = 400V and I_{D} = 40A















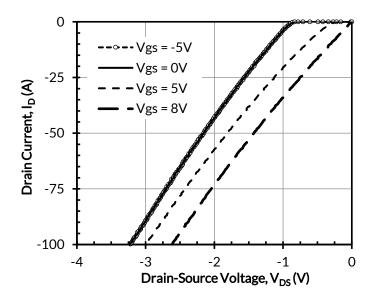


Figure 9. 3rd quadrant characteristics at T_J = -55°C

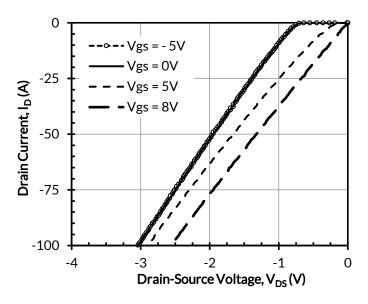


Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C

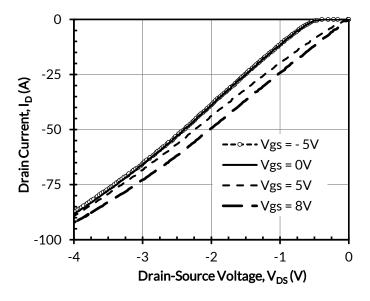


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

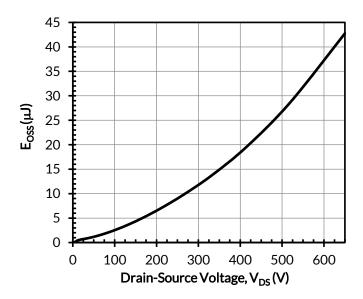


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$





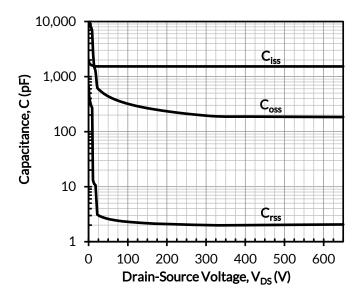








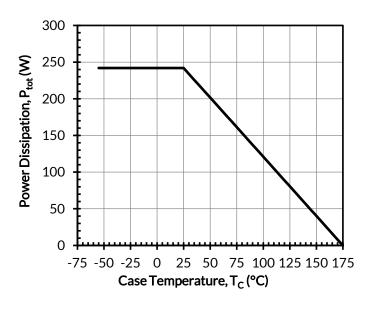




80 70 DC Drain Current, I_D (A) 60 50 40 30 20 10 0 25 50 75 100 125 150 175 -75 -50 -25 0 Case Temperature, T_C (°C)

Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

Figure 14. DC drain current derating



1 Thermal Impedance, $Z_{\theta JC}$ (°C/W) 0.1 D = 0.5D = 0.3**-** D = 0.1 0.01 - D = 0.05 ···· D = 0.02 -D = 0.01Single Pulse 0.001 1.E-06 1.E-05 1.E-04 1.E-03 1.E-02 1.E-01 Pulse Time, t_p (s)

Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance















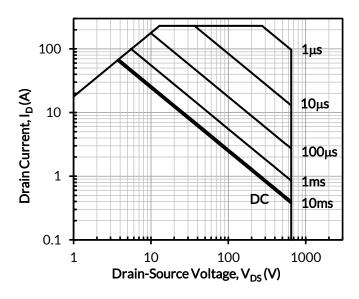


Figure 17. Safe operation area at $T_C = 25$ °C, D = 0, Parameter t_p

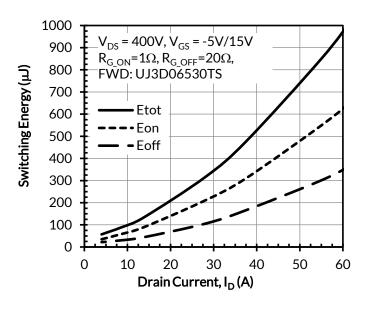


Figure 18. Clamped inductive switching energy vs. drain current at T₁ = 150°C

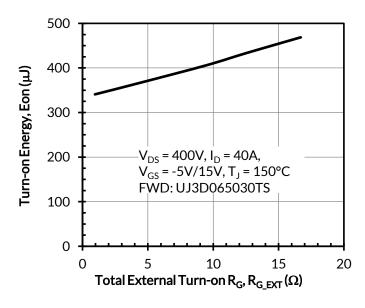


Figure 19. Clamped inductive switching turn-on energy vs. R_{G,EXT ON}

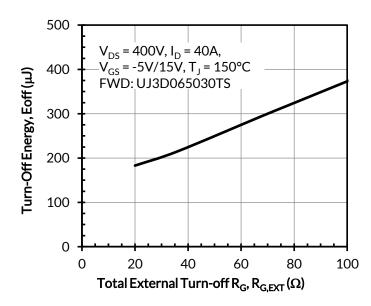


Figure 20. Clamped inductive switching turn-off energy vs. R_{G,EXT OFF}















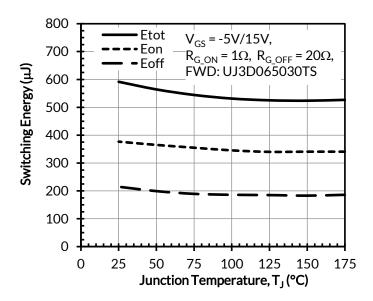


Figure 21. Clamped inductive switching energy vs. junction temperature at V_{DS} =400V and I_{D} = 40A

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (C_{oss}), and reverse recovery charge (C_{oss}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at www.unitedsic.com













Important notice

The information contained herein is believed to be reliable; however, Qorvo makes no warranties regarding the information contained herein and assumes no responsibility or liability whatsoever for the use of the information contained herein. All information contained herein is subject to change without notice. Customers should obtain and verify the latest relevant information before placing orders for Qorvo products. The information contained herein or any use of such information does not grant, explicitly or implicitly, to any party any patent rights, licenses, or any other intellectual property rights, whether with regard to such information itself or anything described by such information. THIS INFORMATION DOES NOT CONSTITUTE A WARRANTY WITH RESPECT TO THE PRODUCTS DESCRIBED HEREIN, AND QORVO HEREBY DISCLAIMS ANY AND ALL WARRANTIES WITH RESPECT TO SUCH PRODUCTS WHETHER EXPRESS OR IMPLIED BY LAW, COURSE OF DEALING, COURSE OF PERFORMANCE, USAGE OF TRADE OR OTHERWISE, INCLUDING THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Without limiting the generality of the foregoing, Qorvo products are not warranted or authorized for use as critical components in medical, life-saving, or life-sustaining applications, or other applications where a failure would reasonably be expected to cause severe personal injury or death.

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Qorvo:

UJ3C065030B3